

# Run13 detector $\alpha$ tests

polar. mtg.  
09.01.13

- BNL 1mm wide strip detectors
- 3 wafers (1699, 1700, 1701), 18 det. each wafer
- Several det. rejected after dark current tests (summary on wiki)
- We have (so far) 30 detectors mounted on ceramic boards

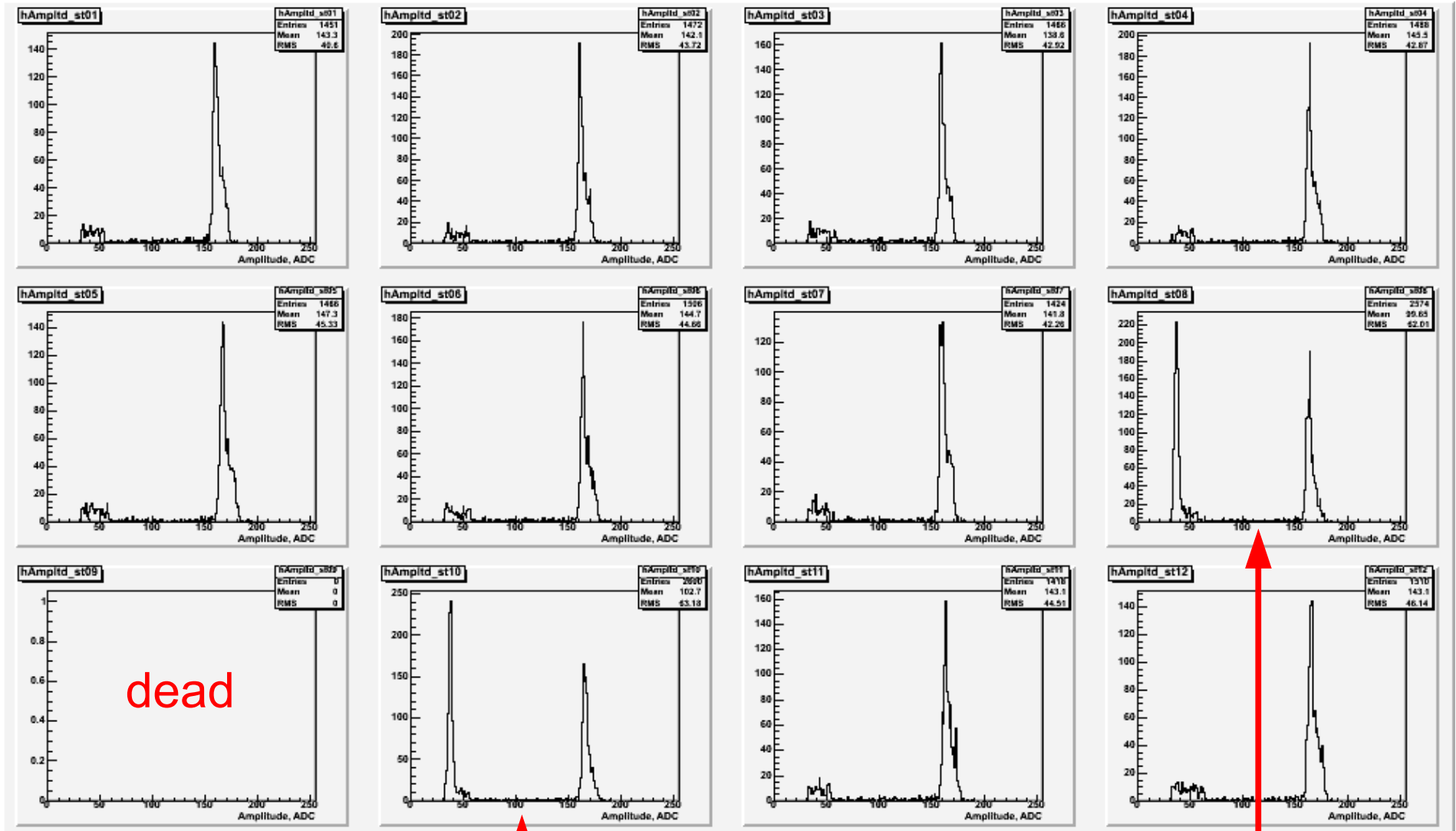
## Tests with $\alpha$ source:

- Test stand in RHIC tunnel (Tony C. & crew)
- Small vacuum chamber with  $^{241}\text{Am}$   $\alpha$  source
- $V_{\text{bias}} = 110 \text{ V}$  (nominal)
- Read out with usual RHIC polarimeter DAQ (yellow)
- 15 minute runs

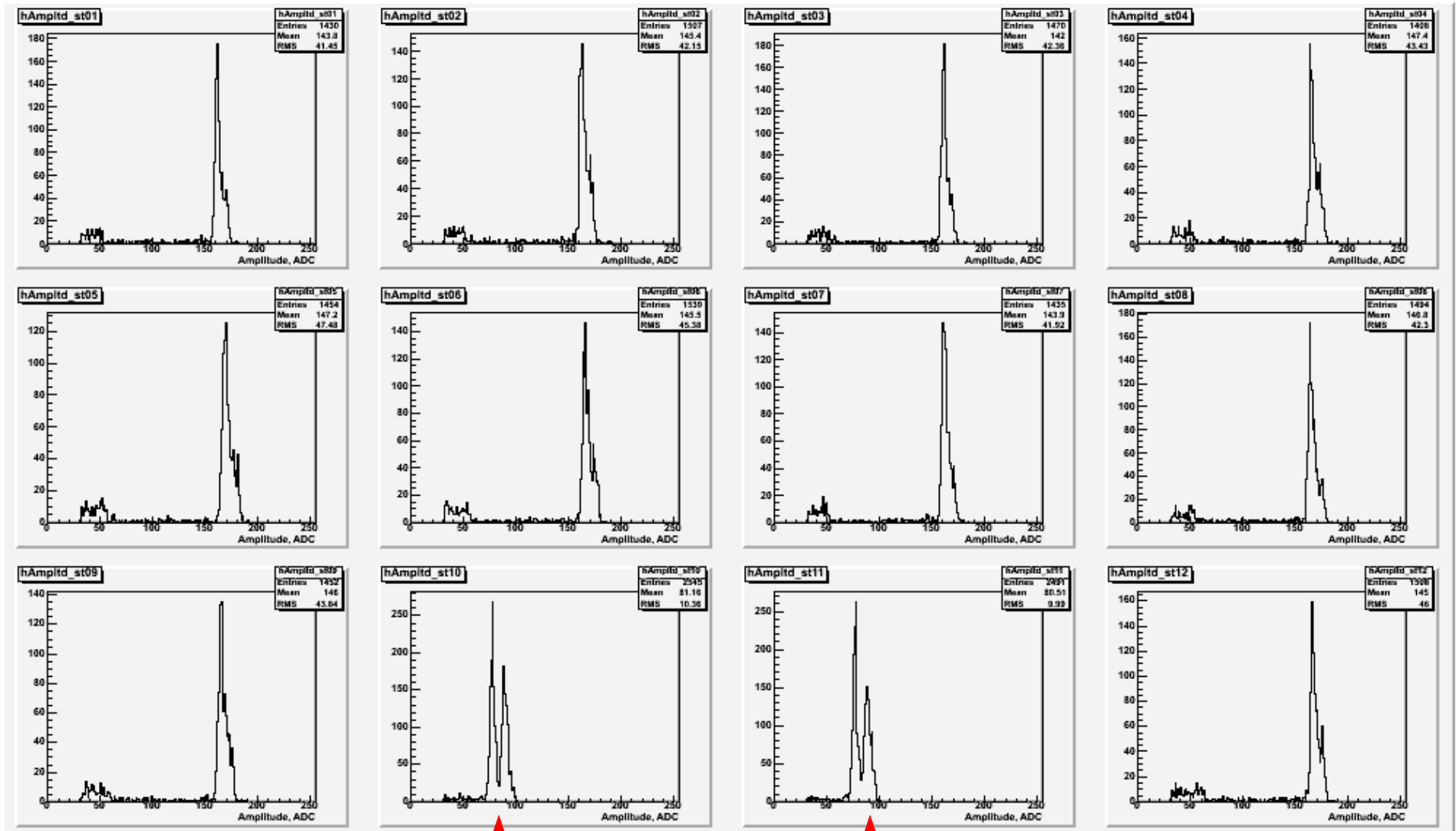
## Results:

- 27 detectors OK as far as  $\alpha$  tests
- Bad detectors: 1700-3 1 dead chan. (chan. 3)  
1701-2 1 dead chan., 2 noisy chan. (next slide)  
1701-6 2 chan.  $\frac{1}{2}$  height  $\alpha$  peak & noisy (next next slide)

# Bad det. 1701-2



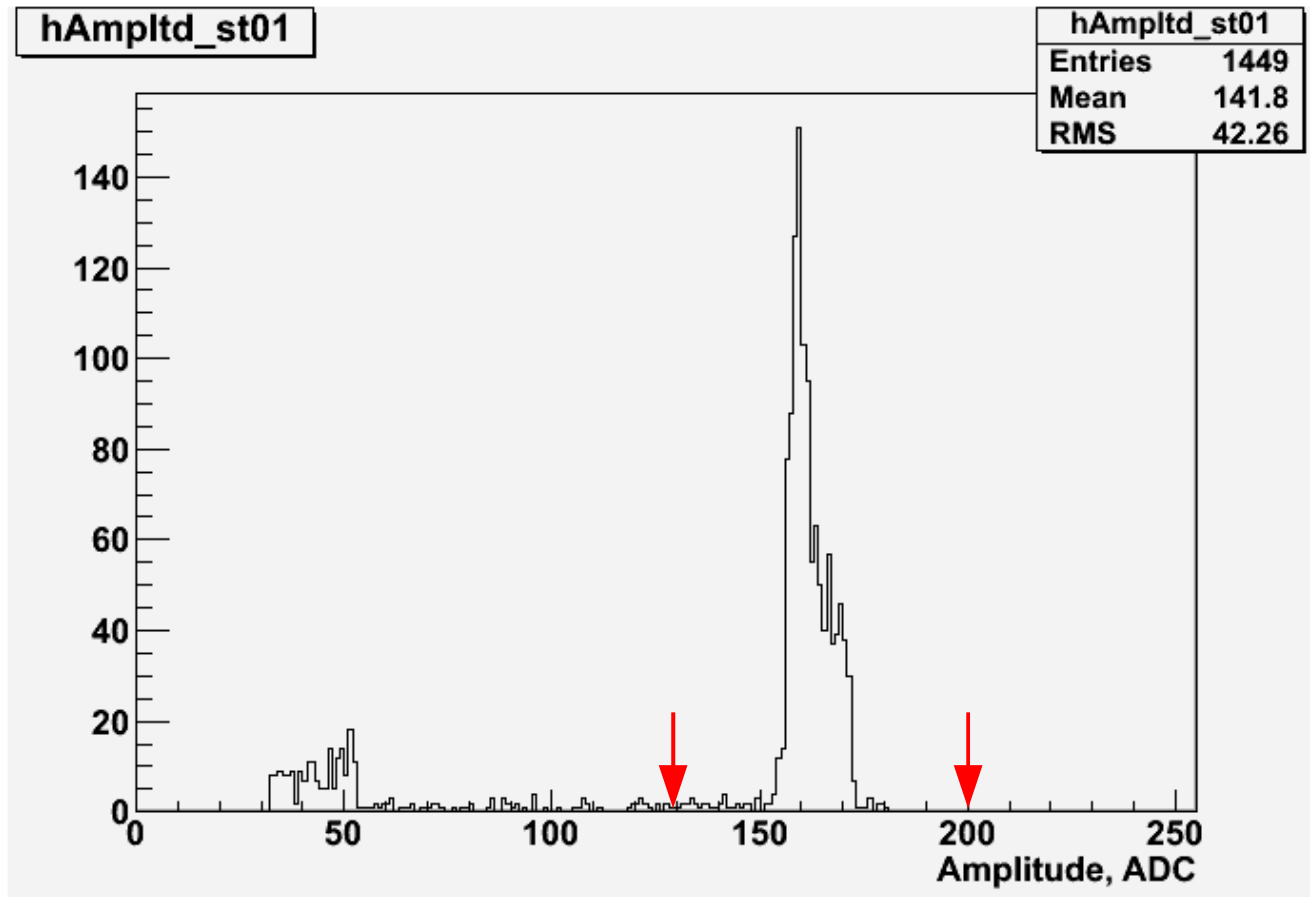
# Bad det. 1701-6



$\frac{1}{2}$  height  $\propto$  peak & noise peak

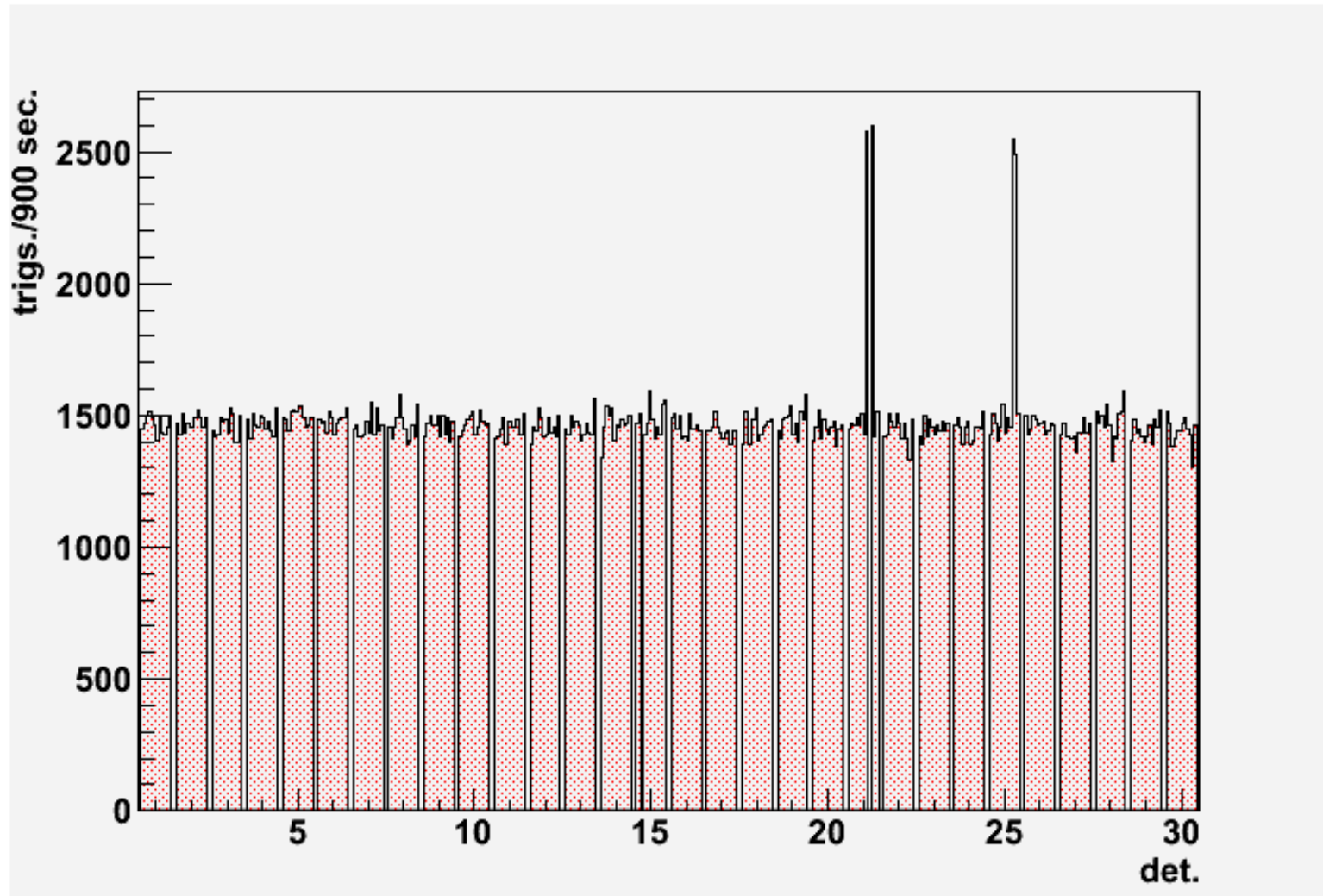
# Summarize

- Most channels nice  $\alpha$  peak like this:



- Summarize all channels: # triggers  
mean in peak region  
RMS in peak region

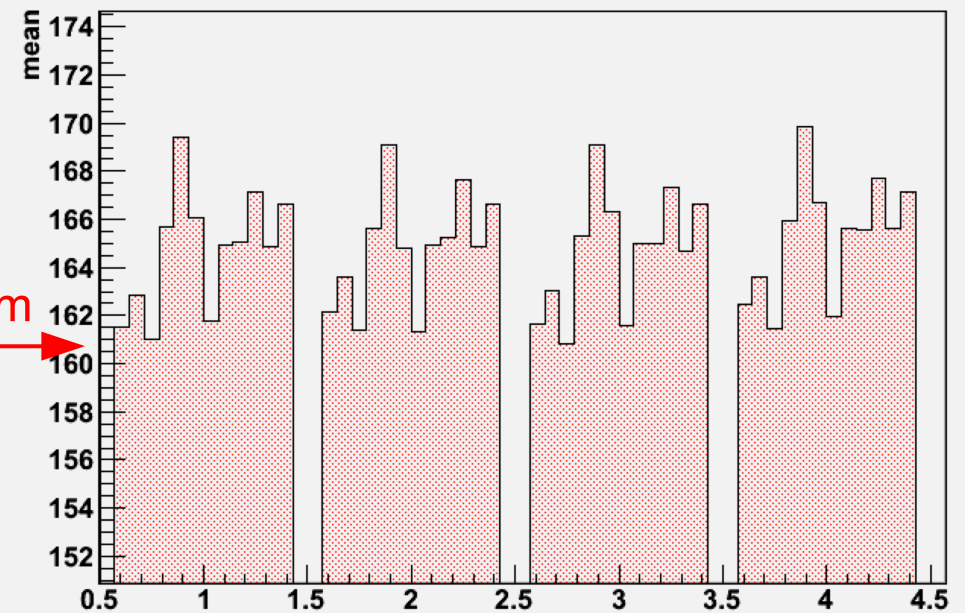
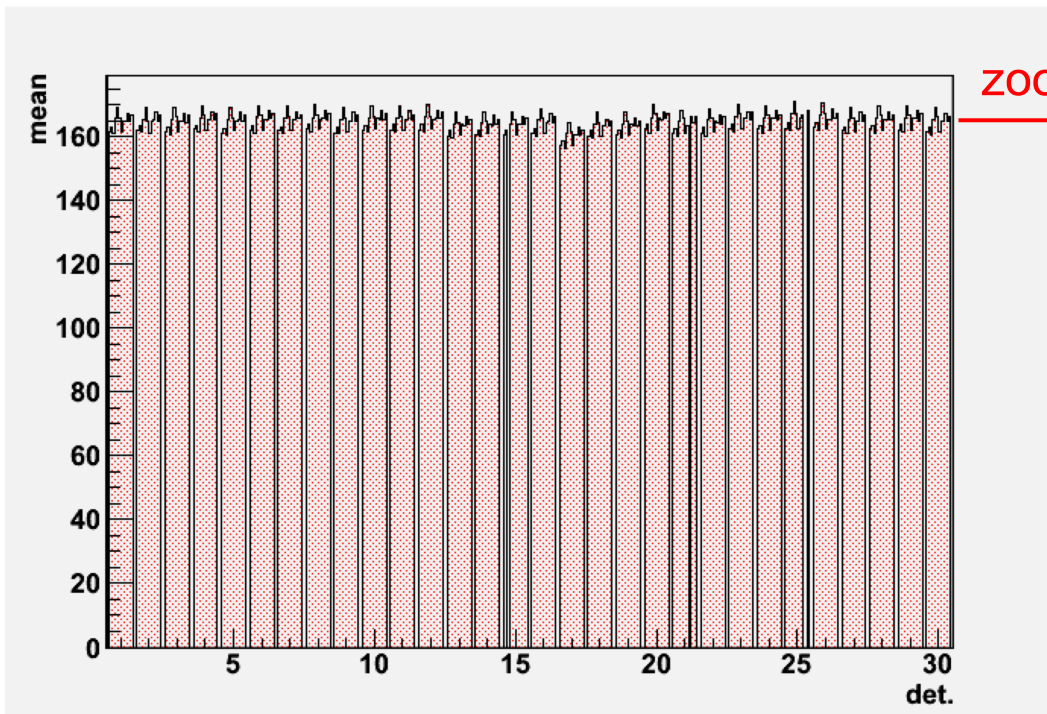
# Summary: #trigs. / chan.



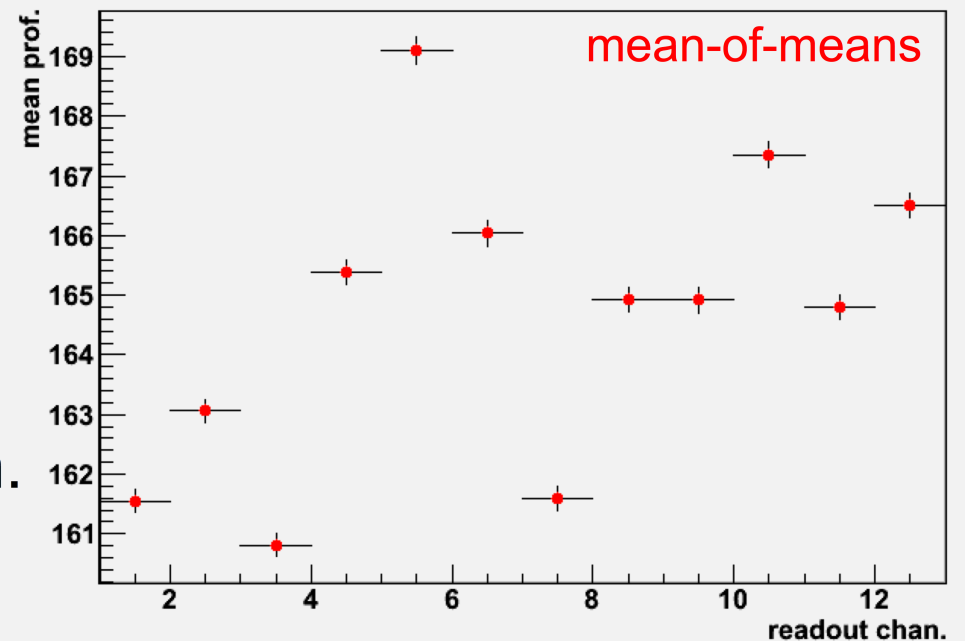
- Except for 4 noisy chans. ~same # triggers per channel ( $\propto$  efficiency)

# Summary: mean / chan.

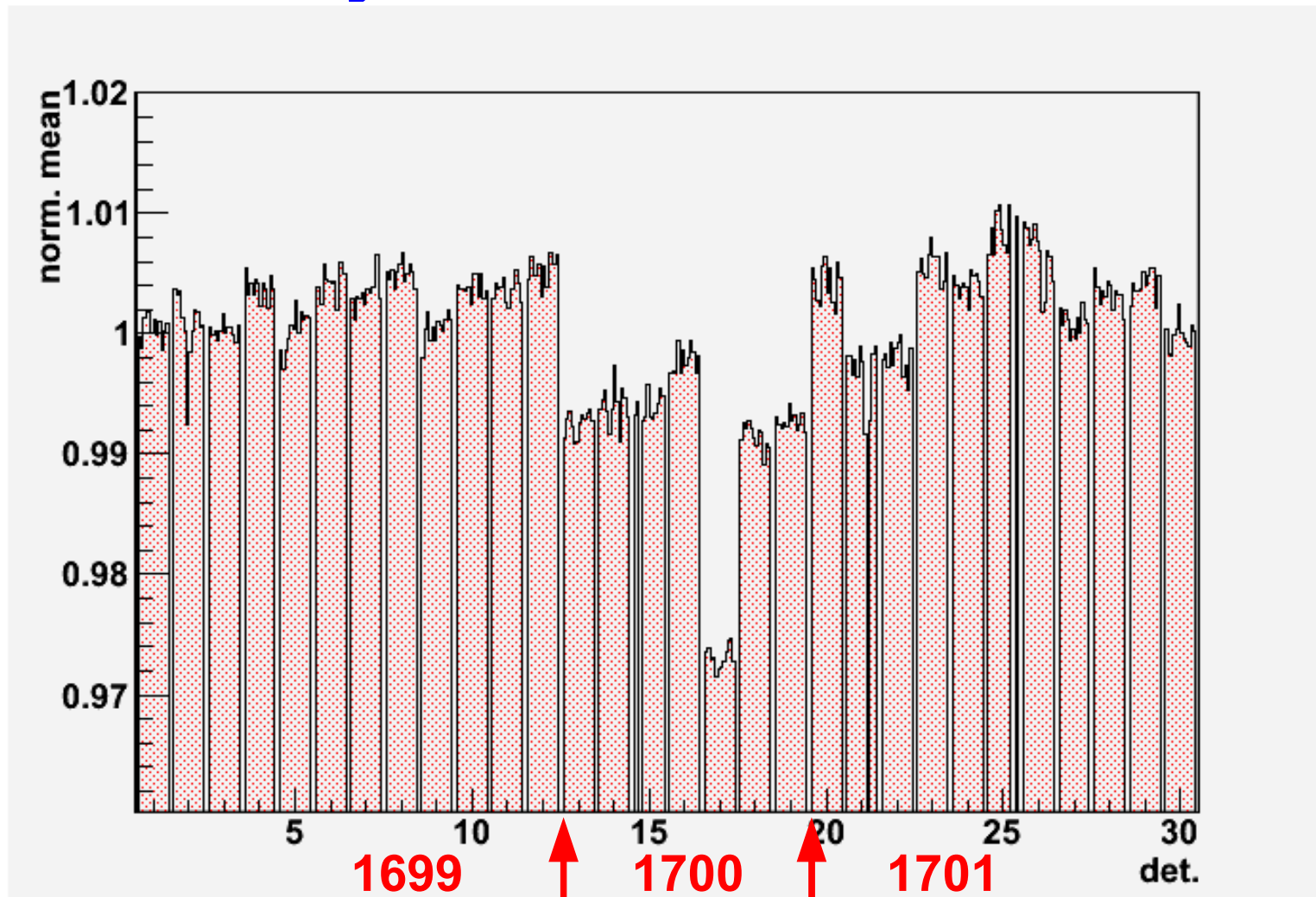
- Mean variations dominated by readout channel variations



- Correct: normalize by “mean-of-means” each readout chan.

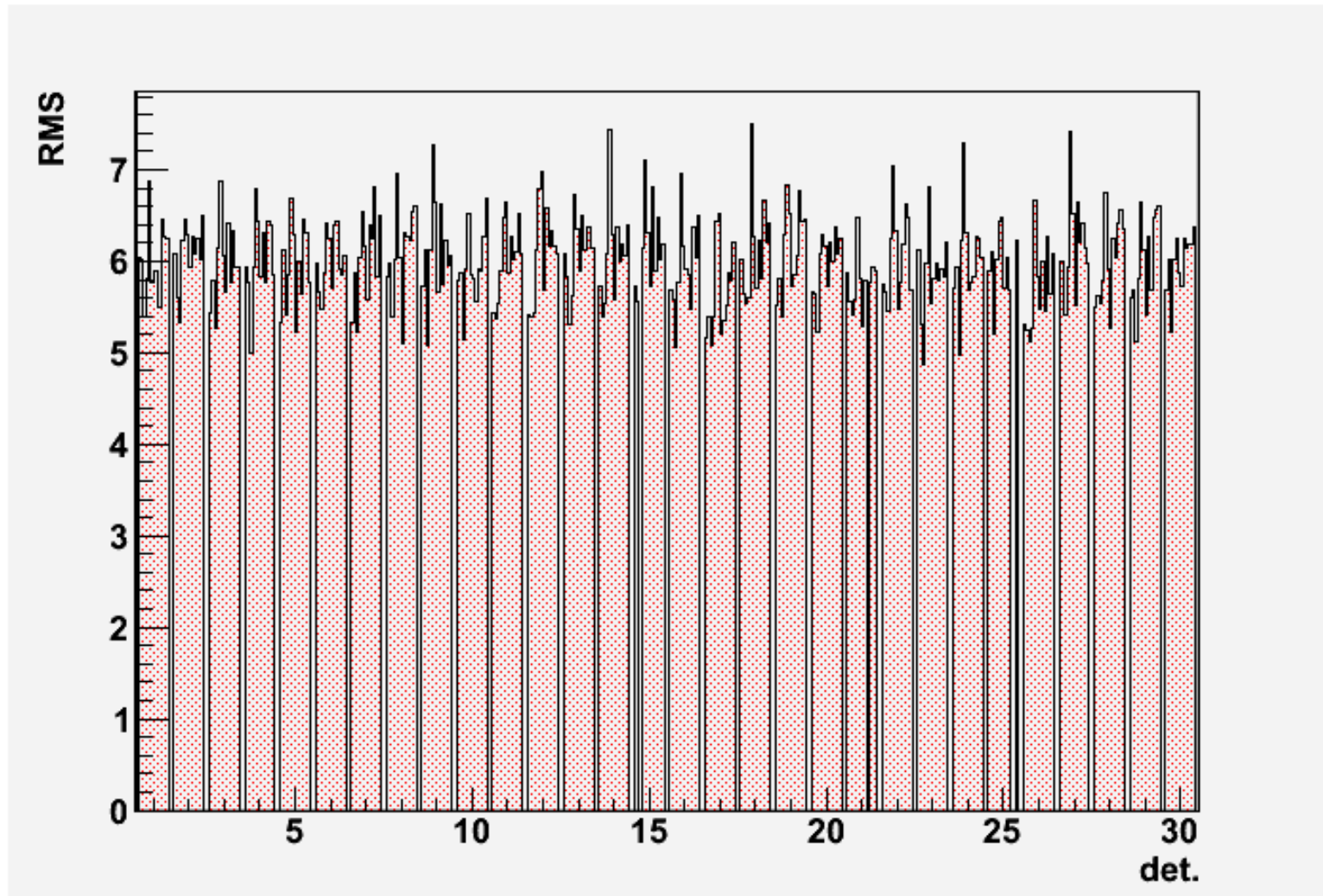


# Summary: norm. mean / chan.



- All means same within  $\pm 1\%$   
except det. 17 = 1700-5  $\sim 3\%$  low
- Wafer-to-wafer systematic variation?

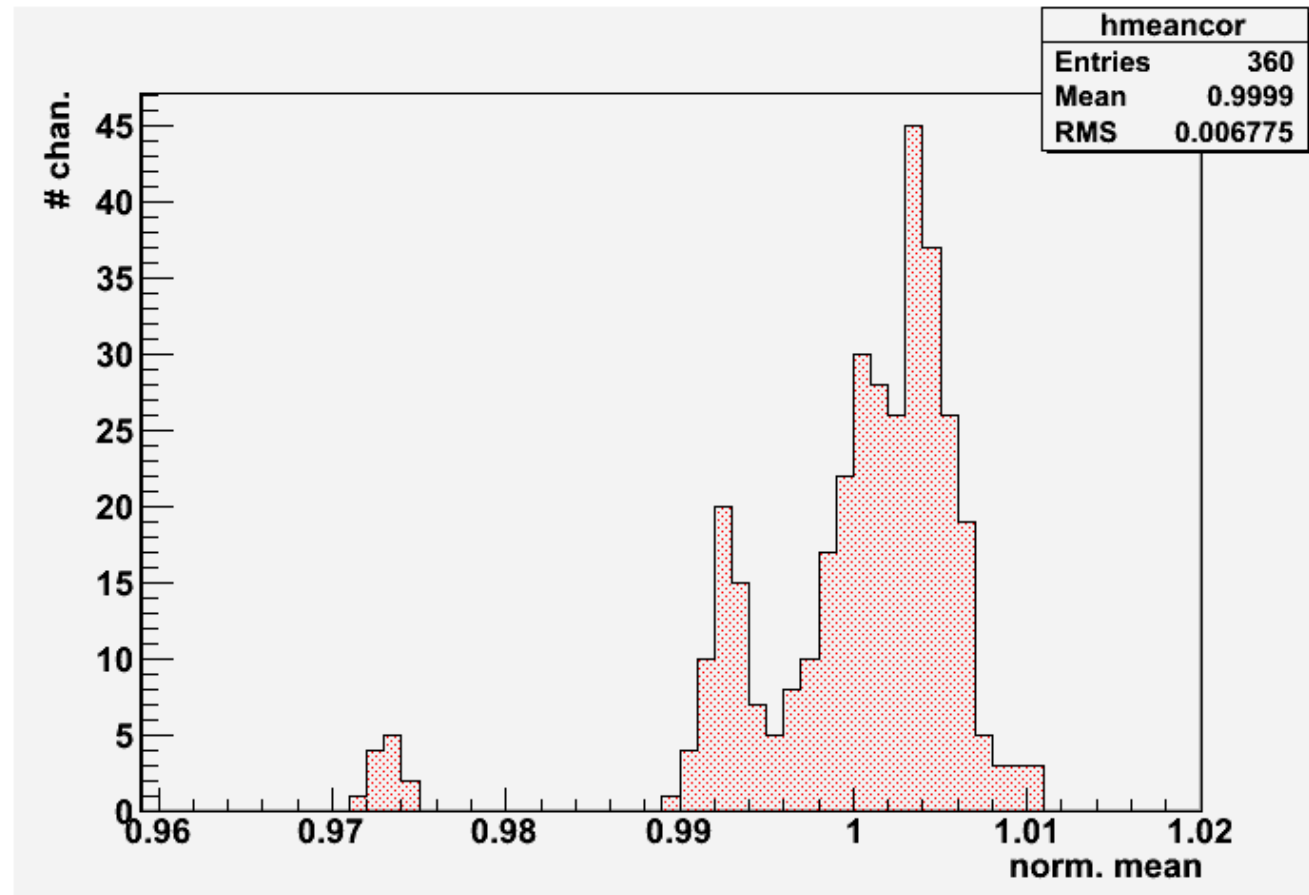
# Summary: RMS / chan.



- All RMS ~same



# Summary: norm. means



# Summary

- Reject detectors w/ dead or noisy chan.:  
1700-3  
1701-2  
1701-6
- Maybe reject detector w/ low ( $\sim 3\%$ ) pulse height:  
1700-5